

Design and Characterization of Cantilevers for Multi-Frequency Atomic Force Microscopy

Steven Ian Moore, Yuen Kuan Yong

The School of Electrical Engineering and Computer Science, The University of Newcastle, Callaghan, NSW 2308, Australia
E-mail: steven.i.moore@uon.edu.au, yuenkuan.yong@newcastle.edu.au

Micro & Nano Letters.

This article presents the experimental characterization of a set of micro-cantilevers targeted at use in multi-frequency AFM. The aim of the work is to design a cantilever that naturally amplifies its harmonic oscillations which are introduced by nonlinear probe-sample interaction forces. This is performed by placing the modal frequencies of the cantilever at integer multiples of the first modal frequency. The developed routine demonstrates the placement of the frequency of the second to fifth mode. The characterization shows a trend that lower order modes are more accurately placed than higher order modes. With two fabricated designs, the error in the second mode is at most 2.26 % while the greatest error in the fifth mode is at 10.5 %.

1. Introduction: Since the invention of atomic force microscope (AFM), it has emerged as one of the most versatile tools for interrogating and studying objects at the nanoscale [1, 2]. AFMs have contributed to breakthroughs in areas such as nano-machining [3], nanometrology [4], material science [5], semiconductor manufacturing [6] and high-density data storage systems [7].

An AFM uses a micro-cantilever, with an extremely sharp probe at its free end, to scan the surface of a sample. The probe-sample interaction forces cause the cantilever to deflect and this deflection is measured to observe the surface topography of the sample.

The need to study dynamic biological processes at high-speed and with low probe-sample interaction force (< 1 nN) has led to the development of dynamic AFM [8]. Among many forms of dynamic AFM, tapping-mode is particularly attractive for imaging soft samples. The tapping cantilever vibrates at its resonance frequency, gently tapping the surface of a sample once per cycle. The vertical feedback loop is used to regulate its oscillation amplitudes. These oscillations are a function of the probe-sample force which in turn is dictated by the probe-sample separation. By compensating for those changes, the vertical feedback control signal can be used to generate high-resolution surface topography of the sample.

Despite the success of AFM, the technique currently faces limitation in terms of spatial resolution and quantitative measurements [9]. It is a challenging task to simultaneously obtain high-resolution topography and mapping of material properties (e.g. stiffness) on soft samples. This is due to the lack of sensitivity or difficulties in separating elastic information from the measured signal [10]. To overcome these difficulties, multi-frequency AFM methods have recently emerged as a new field in force microscopy [9]. Conventional dynamic AFM methods involve the excitation and detection of a single frequency component (usually the fundamental mode) of the cantilever's deflection. As a result, the information about the sample's properties that is encoded in the deflection at frequencies other than the excitation frequency is lost. Multi-frequency AFM methods involve the excitation and/or detection of several frequencies. Different resonances (modes) act as signal channels that provide access to different material properties, including topography, elastic modulus, and electrostatic and magnetic forces [11].

One approach to multi-frequency AFM is to use higher order harmonics for imaging. The higher order harmonic components of the cantilever's deflection are introduced due to the nonlinear probe-sample interaction forces. The amplitude of the harmonic vibrations decreases by approximately $1/n$ (n is the order of harmonics) [9]. These small harmonic vibrations become difficult to detect.

To naturally amplify these harmonics, a number of researchers have designed harmonic probes/cantilevers whose modal frequencies lie at integer multiples of the fundamental frequency [12, 13, 14, 15, 16].

Initial design approaches parameterized the cantilever in terms of the dimensions of various topological features [12, 13, 14]. By systematically varying these parameters while performing modal analysis, a relationship between these parameters and the modal frequencies is formed. This approach heavily restricts the design space and limits the frequency placement to only a single mode.

A more flexible approach is to form a structure as set of finite elements and, via an optimization routine, vary properties or dimensions of the elements to design the cantilever. Cai et al. [16] splits the cantilever into Euler-Bernoulli beam elements and optimization sets the width of each element. The use of beam elements ignores torsional modes and only modifies the boundary of the cantilever, not the topology, restricting potential solutions. Xia et al. [15] applies the level set method to place the modal frequencies allowing for arbitrary 2D topologies to be formed. However only the placement of one modal frequency at a high order harmonic (the 16th) is demonstrated. Furthermore the curved topologies produced by the level set method are difficult to fabricate using microfabrication.

The non-convex mapping between the topology and the modal frequencies [17] presents an issue for the gradient-based-optimization used by Xia et al. [15] and Cai et al. [16]. For non-convex cost functions, gradient-based-optimization tends to converge to locally optimal solutions. And for complex cost functions and constraints, the definition of the gradient of the cost function is difficult to derive or doesn't exist.

This work develops a topology optimization routine for an AFM cantilever. The aim of the optimization routine is to place several modal frequencies at integer multiples of the fundamental frequency. The cantilever is modeled using the finite element (FE) method and a genetic algorithm is used to form the topology of the cantilever. The proposed optimization routine provides a number of benefits over existing routines for harmonic cantilever designs. It provides the flexibility to place multiple modal frequencies simultaneously. This work demonstrates the placement of four modes (the second to the fifth) at integer multiples of the first. This includes both flexural and torsional modes. The use of the genetic algorithm provides advantages over gradient-based optimization routines. The genetic algorithm is a simple stochastic search that performs a global search, easily handles the complex relationship between the modal frequencies and the cantilever's topology and is well suited to handling the discrete variables that

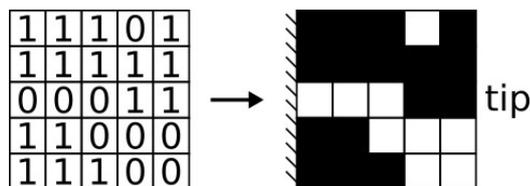


Figure 1 A binary matrix represents the topology of the cantilever. The clamped edge of the cantilever is on the left side of the matrix, and a set of elements are designated to be the tip of the cantilever.

are used to represent the topology. The optimization routine can produce arbitrary 2D topologies and the resulting designs are easily fabricated using microfabrication.

The article is organized as follows. Section 2 briefly outlines the process used to model the cantilever and perform modal analysis. Section 3 outlines how the cantilever topology is represented. Section 4 provides details of the genetic algorithm used to modify the topology to place the modal frequencies of the cantilever. Section 5 describes two designs that resulted from the execution of the optimization routine. The cantilevers were fabricated and the experimental characterization of the designs is presented in Section 6.

2. Mindlin plate theory and the finite element method:

Of concern in this work is the location of the modal frequencies of the AFM cantilever. Modeling only the elastic behavior of a structure results in a conservative system in which harmonic solutions $x(t) = u \cos(\omega t)$ exist under no external force or load. The amplitude u is the mode shape with a modal frequency ω .

The cantilever is modeled using the Mindlin plate theory [18] to accurately account for arbitrary two dimensional topologies and to capture the torsional and plate modes that exist in AFM cantilevers [19]. The finite element (FE) method [20, 18] is applied to analyze the structure.

The cantilever is discretized as a set of four node rectangular Mindlin plate elements. The nodes in the corners of the rectangular element are parameterized by three degrees-of-freedom: the deflection in the z-axis, rotation in the x-axis and rotation in the y-axis. The x and y axes are along the width and length of the plate respectively, and the z-axis is along the thickness of the plate. For analysis of an individual element, the coordinate system of the element is mapped from (x, y) to (ξ, η) by placing the origin at the center of the element and placing the nodes at coordinates $(-1, -1)$, $(1, -1)$, $(1, 1)$ and $(-1, 1)$. In the (ξ, η) coordinate system, the FE shape functions employed are

$$N_i(\xi, \eta) = \frac{1}{4}(1 + \xi_i \xi)(1 + \eta_i \eta) \quad i = 1, \dots, 4 \quad (1)$$

where (ξ_i, η_i) are the coordinates of the nodes. Using these shape functions and the Mindlin plate theory, the mass and stiffness element matrices are derived. The mass and stiffness element matrices for each element are assembled into the system

$$M\ddot{x} + Kx = 0 \quad (2)$$

for degrees-of-freedom x , mass matrix M and stiffness matrix K . The boundary conditions for the cantilever enforce zero deflection and rotation for each node along the clamped boundary. Non-trivial harmonic solutions $x(t) = u \cos(\omega t)$ for the above system satisfies the eigenvalue problem

$$Ku = \lambda Mu \quad (\lambda = \omega^2). \quad (3)$$

The matrices K and M are sparse allowing this eigenvalue problem to be solved using the Lanczos algorithm implemented in the software ARPACK. The numerical computations provide the modal frequency ω and if desired the mode shape u .

3. Cantilever representation for optimization: To design the cantilever, a fixed rectangular mesh is formed to denote the design space. Fixed sized elements are added or removed from the mesh. This allows the cantilever to be represented as a binary matrix as shown in Figure 1. Each element represents a rectangular portion of the cantilever. If the element has a value of 1, the area is filled with material, if 0, it is void. The mesh used for the topology representation maps directly to the mesh used for FE analysis allowing for fast FE meshing and assembly.

The modification of the binary matrix during the optimization routine does not guarantee that the resultant design features a cantilever topology. To ensure that the design is feasible before carrying out the FE analysis, an image processing routine [21] is applied to the cantilever topology.

A region identification routine is applied to the binary matrix to find all the separate structures in the topology. A region is deemed connected if it includes the tip and borders the clamped edge. n_c is the number of connected regions and n_d is the number of disconnected regions. A feasible design must have $n_c = 1$ and $n_d = 0$. Elements with only one neighboring element, denoted hinges, are discouraged. n_h is the number of hinges and $n_h = 0$ for a design to be feasible. Additional metrics A_d , the total area of the disconnect structures, and A_m , the area of the smallest structure, are generated for use in the optimization.

In the example shown in Figure 1, $n_c = 1$, $n_d = 1$, $n_h = 2$ and $A_d = A_m = 5$.

4. Optimization with the genetic algorithm:

The objective of the optimization routine is to place the modal frequencies of the cantilever at integer multiples of the first modal frequency. To increase the speed of convergence, the optimization routine is applied to a specified initial cantilever topology and moves its modal frequencies to the nearest integer multiple of the first.

The cantilever representation x is a binary matrix as described in Section 3. Since symmetry is enforced, x represents half of the cantilever and the full topology is generated for the image processing routine and FE analysis. The optimization problem

$$\min \quad f(x) = \sum_{i=2}^M w_i \left(\frac{\lambda_i}{\lambda_1} - r_i^2 \right)^2 \quad (4)$$

$$\text{s.t.} \quad x \in \Omega_f \quad (5)$$

seeks to minimize the error in modal frequency ratios while rejecting invalid designs. M is the number of modes to place, w_i are weights for each term in the cost function, λ_i are the eigenvalues of the cantilever FE model, r_i are the desired frequency ratios, Ω_f is the set of feasible cantilever designs.

The optimization problem is a binary nonlinear weighted least squares problem. The genetic algorithm was selected due to its natural affinity to operate on binary variables, ease at handling nonlinear cost functions, lack of requirement of the gradient of the cost function, ability to perform a global search and ability to enforce the feasible set of cantilever designs. Genetic algorithms have been applied in structural design to achieve objectives such as compliance minimization and eigenfrequency maximization [22, 23, 21, 24, 25].

The use of the genetic algorithm simplifies the optimization routine compared to gradient-based-optimization methods [17, 15, 16] previously applied to harmonic cantilever design. The stochastic nature of the genetic algorithm allows for a global search without the risk of converging to local minima and the only requirement of the cost function $f(x)$ is that it can be computed, no further analysis is required.

The optimization problem is moved from a constrained to an unconstrained problem by applying a penalty to infeasible designs.

Algorithm 1 The cantilever design genetic algorithm.

```

1: procedure GENETIC ALGORITHM
2:   Generate cantilevers in the initial generation
3:   for each generation do
4:     Evaluate the fitness of each cantilever
5:     Select elite cantilevers for the next generation
6:     Select cantilevers for the crossover operator
7:     Crossover cantilevers to produce the next generation
8:     Mutate cantilevers resulting from the crossover operator
9:   end for
10: end procedure
  
```

The optimization problem is restated with the cost function [21]

$$\min F(x) = \begin{cases} f(x) & x \in \Omega_f \\ f^* + viol(x) & otherwise \end{cases} \quad (6)$$

where

$$viol(x) = \Gamma_d n_d + \Gamma_a A_d + \Gamma_m A_m + \Gamma_h n_h. \quad (7)$$

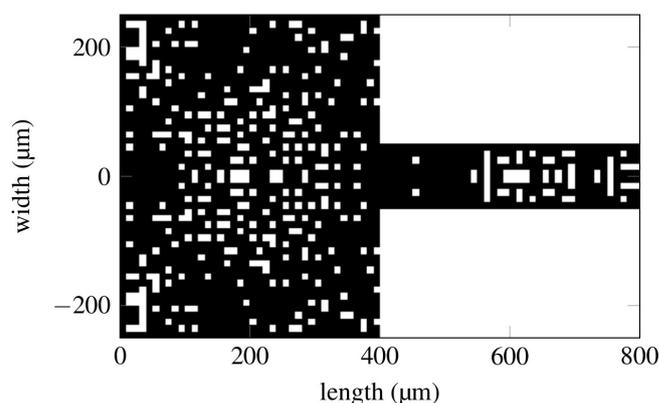
f^* is a large constant to ensure all infeasible designs have a worse cost function than that of feasible designs and the parameters Γ_d , Γ_a , Γ_m and Γ_h are weighting values to penalize each undesirable metric in the violation function. The outline of the genetic algorithm is shown in Algorithm 1. Many of the heuristics employed in the genetic algorithm are a result of the small size of the feasible set Ω_f compared to the full set of binary matrices.

The initial generation of cantilevers are all identical. This was deemed necessary as randomly generated structures tend to be infeasible. The mutation operator is necessary to create new designs in early generations. The genetic algorithm uses linear ranking to evaluate the fitness of each design. Rank based fitness is particularly important due to the large penalty f^* given to infeasible designs. Elitism is employed to ensure the best designs are not lost. The parent cantilevers for the crossover operator are selected using the stochastic universal sampling. Uniform crossover is performed to produce the next generation of cantilevers. The mutation operator flips bits with a low probability. Mutation is only employed to non-void regions of the initial cantilever as the existence of material in large void regions of the binary matrix is highly likely to produce an infeasible design. The genetic algorithm is terminated after a fixed number of generations and the cantilever with the lowest cost function is selected.

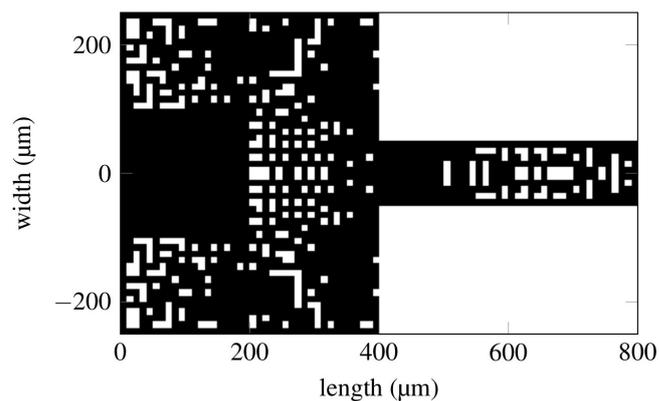
5. Cantilever designs using optimization: The initial cantilever design that is to be modified with the genetic algorithm is shown in Figure 2 (a). The base section of this initial design is 400 μm long and 500 μm wide. The tip section is 400 μm long and 100 μm wide. Material properties used to model the cantilever are those of the silicon layer from the PiezoMUMPs microfabrication process provided by MEMSCAP [26]. Here, the thickness of the layer is 10 μm , the elastic modulus is 169 GPa, the density is 2500 kg m^{-3} and Poisson's ratio is 0.29. Finite elements that are used to form the topology are 10 μm long and 10 μm wide. The dimension of the FEM model of the initial cantilever design is 7440.

Modal frequencies of the initial design are tabulated in Table 1 (a) and the mode shapes are shown in Figure 3. With this design, the frequency ratio setpoints r_i , introduced in Equation (4), are chosen to be (3, 4, 8, 13).

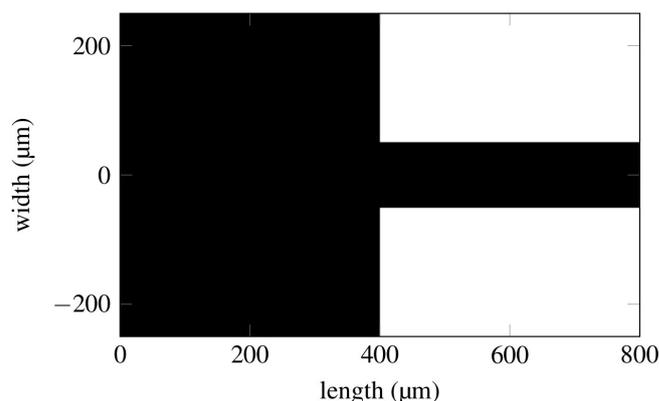
The genetic algorithm is applied to mutate the initial cantilever design. A population of 20 individuals is used for each generation, elitism moves 2 individuals to the next generation, uniform crossover swaps bits with a 50 % probability and mutation flips bits with a 1 % probability. The optimization problem is executed for 500 generations in less than half an hour.



(a) The initial cantilever topology.



(b) The first optimized cantilever design.



(c) The second optimized cantilever design.

Figure 2 (a) Initial cantilever design that is modified with the genetic algorithm to move its modal frequencies down to integer multiples of the first modal frequency. (b) The execution of the genetic algorithm results in this first optimal cantilever design. (c) Modification was made where a large square area is preserved to allow for a piezoelectric layer to be added to the design.

The first optimized cantilever design with a stiffness of 17.68 N m^{-1} is shown in Figure 2 (b). From the FE modal analysis, the modal frequencies of the first optimized design are tabulated in Table 1 (b). Errors in the frequency ratios are smaller compared to the initial design, and the frequency ratios of the cantilever have approached integer values. The checkerboard pattern results due to the binary matrix representation of the cantilever topology. The features size limit for the PiezoMUMPs microfabrication process is 2 μm therefore there is no difficulty etching the 10 μm square holes in the topology.

Self-actuation and self-sensing cantilevers provide great advantages in terms of robust Q control in tapping-mode AFM [27]. It has the potential to reduce the physical size of an AFM

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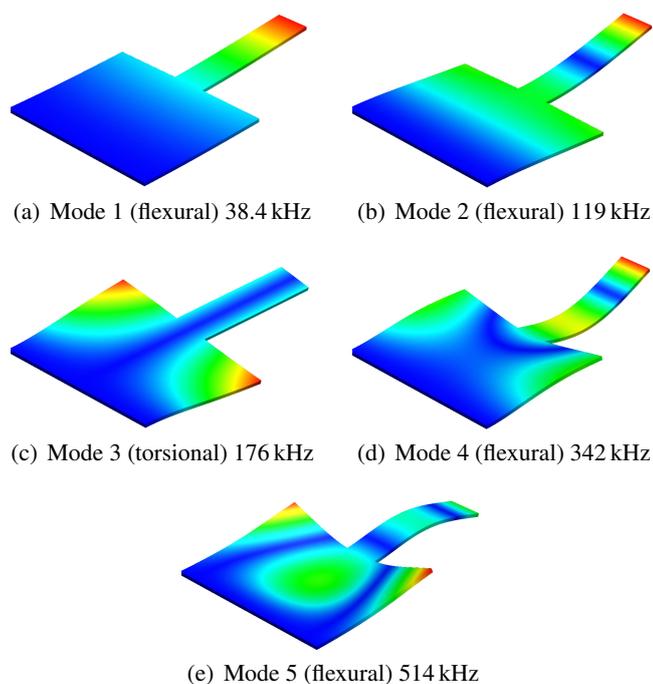


Figure 3 The cantilever modes of the initial cantilever topology from finite element analysis.

by eliminating its optical components [28]. A piezoelectric layer is often laminated on the cantilever to serve as both actuator and sensor. In the first design proposed in this work, it is difficult to lay a piezoelectric layer on the cantilever due to its checkerboard pattern. As a result, modifications are made in the second design where an area is preserved to allow space for the piezoelectric layer. This is realized by preventing the mutation operator in the genetic algorithm from acting within this designated area. The resultant design is shown in Figure 2 (c). The modal frequencies of the second design are shown in Table 1 (c). Again, the frequency ratios lie close to integer values. The stiffness of the second optimized cantilever design is 17.77 N m^{-1} .

6. Experimental characterization: The cantilevers were fabricated with the PiezoMUMPs microfabrication process provided by the company MEMSCAP [26]. Fabrication starts with a double-sided silicon-on-insulator wafer. The top $10 \mu\text{m}$ layer of silicon is doped. A $0.2 \mu\text{m}$ oxide layer is grown and patterned with a reactive ion etch (RIE) to insulate the silicon layer. Next a $0.5 \mu\text{m}$ piezoelectric layer of aluminium nitride is deposited and patterned with a wet etch. To provide electrical connections, a $1 \mu\text{m}$ layer of aluminium is deposited and patterned using a lift-off process. The device is then etched into the silicon layer using a Deep RIE. And finally the device is released by etching through through the bottom $400 \mu\text{m}$ silicon layer using multiple etching processes. A scanning electron microscope (SEM) (Hitachi TM3000) is used to image the fabricated cantilevers. The displacement of the cantilevers, for identification of the cantilever’s frequency response, was measured using a laser Doppler vibrometer (Polytec MSA-400).

SEM images of the fabricated designs are shown in Figure 4. To actuate the first cantilever design, the cantilever is appended to a large base as shown in Figure 4 (a). A piezoelectric transducer is layered over the base plate to excite the cantilever. The area under the cantilever and the base is trenched. As a result, three sides of the base, which are located at the edge of the trench, are fixed. It is assumed that the effect of the base on the cantilever’s dynamics is negligible.

Table 1 From FE modal analysis, the Modal frequencies of the initial cantilever and the two optimized cantilevers.

(a) Modal frequencies of the initial design.				
mode	freq. (Hz)	ratio	error (%)	type
1	38379			flexural
2	119088	3.103	3.43	flexural
3	175832	4.581	14.5	torsional
4	341535	8.900	11.3	flexural
5	514128	13.40	3.08	flexural
(b) Modal frequencies of the first optimized design.				
mode	freq. (Hz)	ratio	error (%)	type
1	35860			flexural
2	107093	2.986	0.47	flexural
3	143833	4.010	0.25	torsional
4	287127	8.006	0.08	flexural
5	466294	13.00	0.00	flexural
(c) Modal frequencies of the second optimized design.				
mode	freq. (Hz)	ratio	error (%)	type
1	35889			flexural
2	107559	2.997	0.10	flexural
3	143950	4.011	0.28	torsional
4	287208	8.003	0.04	flexural
5	466449	13.00	0.00	flexural

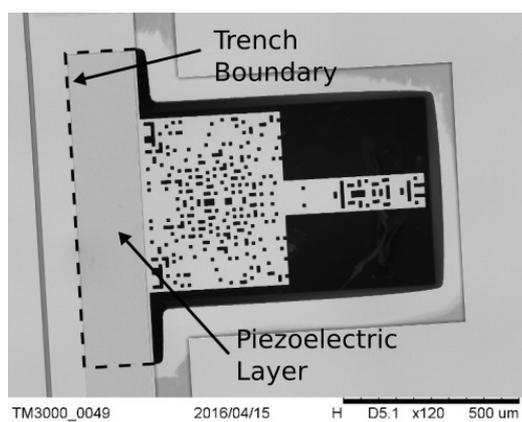
Table 2 Experimentally determined modal frequencies and their ratios with respect to the fundamental frequency of the cantilever.

(a) Modal frequencies of the first cantilever design.			
mode	frequency (Hz)	ratio	error (%)
1	30000		
2	92031	3.068	2.26
3	122031	4.068	1.70
4	239063	7.969	0.39
5	348906	11.63	10.5
(b) Modal frequencies of the second cantilever design.			
mode	frequency (Hz)	ratio	error (%)
1	39688		
2	116875	2.945	1.83
3	150469	3.791	5.23
4	311719	7.854	1.82
5	464531	11.70	10.0

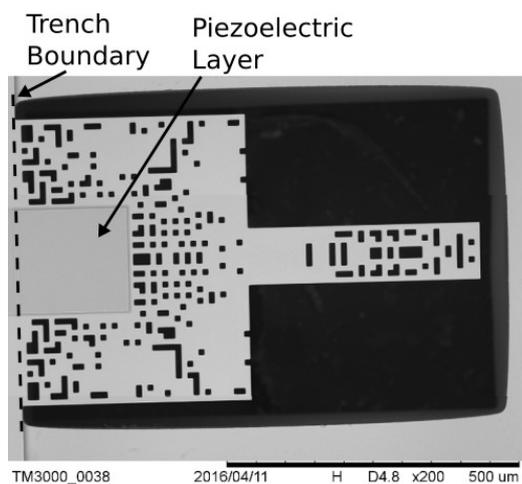
The purpose of the second optimized cantilever design was to allow space for a piezoelectric transducer on the cantilever. The SEM image in Figure 4 (b) shows the cantilever design with a piezoelectric layer in the designated rectangular space. The piezoelectric layer was assumed insignificant compared to the cantilever silicon layer due to its small thickness and area compared to the silicon layer. As a result, no modification of the FEM model was made to account for the laminate structure formed by the piezoelectric layer.

On both cantilevers, the piezoelectric transducer was excited with a 0.3 V periodic chirp. The displacement of the induced motion was measured at the end of the cantilever. The magnitude responses from voltage to displacement are shown in Figure 5. The modes of the cantilevers can be seen clearly in the measured magnitude responses.

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(a)



(b)

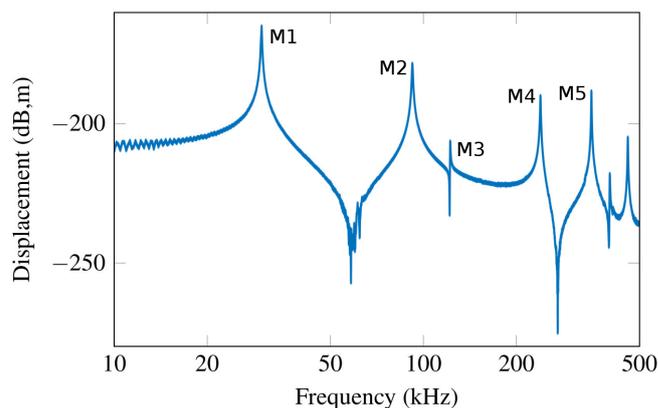
Figure 4 SEM images of the fabricated (a) first and (b) second cantilever designs.

The modes of the cantilevers were identified and their corresponding frequency, frequency ratio with respect to the first modal frequency and percentage error from the desired frequency ratio are tabulated in Table 2.

For the first cantilever design, the modal frequencies have decreased due to the presence of the base plate. Nevertheless, the frequency ratios are relatively precise for the second, third and fourth mode. Though ultimately to produce more accurate results the base plate should be incorporated into the FEM modeling. For the second cantilever design, the error in the mode 3 frequency ratio has increased compared to the first design. Here the piezoelectric layer has had a significant effect. The largest frequency ratio error in both cantilevers is for mode 5. This is attributed to fabrication tolerances, in particular, the etching process of the trench area exhibits large dimensional variations, which is up to $50\ \mu\text{m}$ in one direction [26]. This variation shifts the clamped boundary of the cantilever, which in turn, changes its modal frequencies.

7. Conclusion: This work has outlined the design and characterization of two harmonic cantilevers for multi-frequency AFM applications. These cantilevers amplify the harmonics produced during the nonlinear probe-sample interaction forces. Compared to previous harmonic cantilever designs, this work demonstrates a routine which is capable of placing several modal frequencies simultaneously at an integer multiples of the fundamental frequency. Furthermore, the routine is simple to implement and it can be used to place both torsional and flexural modes. It does not require the derivation/evaluation of gradients

(a) Frequency Response of First Optimized Design



(b) Frequency Response of Second Optimized Design

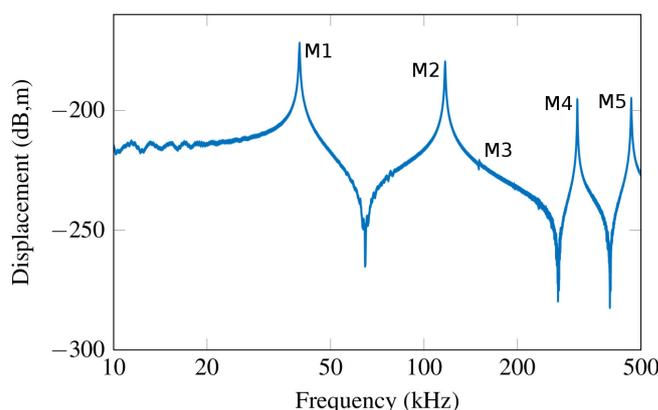


Figure 5 Magnitude response of the (a) first and (b) second optimized cantilever designs. The torsional mode (mode 3) may not be observable on this plot but is distinguishable with careful analysis of the measurements.

or differential equations. The discrete design variables provide for quick finite element meshing.

The stochastic nature of the genetic algorithm is well suited to the design of harmonic cantilevers. The complex relationship between the parameters of the topology and its modal frequencies make the black box nature of the genetic algorithm ideal to perform a global search. Furthermore, no consideration of the optimization algorithm is needed when parameterizing the topology. The algorithm can handle additional design goals easily.

The experimental results show the accurate placement of mode 2, 3 and 4 in the first cantilever design and mode 2 and 4 in the second cantilever design. Future work aims to account for fabrication and material property variances in the optimization routine and include modeling the piezoelectric layer and AFM probe tip to improve the robustness and accuracy of the design routine.

8 References

- [1] Wiesendanger R.: 'Scanning probe microscopy and spectroscopy', 1994, Cambridge University Press
- [2] Yong Y. K., et al.: 'Invited Review Article: High-speed flexure-guided nanopositioning: Mechanical design and control issues', *Review of Scientific Instruments*, 2012, **83**, (12), 121101
- [3] Devasia S., Eleftheriou E., Moheimani S. O. R.: 'A Survey of Control Issues in Nanopositioning', *Control Systems Technology, IEEE Transactions*, 2007, **15**, (5), pp. 802–823
- [4] Mazzeo A. D., et al.: 'Atomic force microscope for accurate dimensional metrology', *Precis. Eng.*, 2009, **33**, (2), pp. 135–149

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- [5] Yamanaka K., et al.: 'Quantitative material characterization by ultrasonic AFM', *Surf. Interface Anal.*, 1999, **27**, pp. 600–606
- [6] Choi K-B., Lee J. J.: 'Passive compliant wafer stage for single-step nano-imprint lithography', *Rev. Sci. Instrum.*, 2005, **76**, 075106.
- [7] Sebastian A., et al.: 'Achieving Subnanometer Precision in a MEMS-Based Storage Device During Self-Servo Write Process', *Nanotechnology, IEEE Transactions on*, 2008, **7**, (5), pp. 586–595
- [8] Lozano J. R., Garcia R.: 'Theory of Multifrequency Atomic Force Microscopy', *Physical Review Letters*, 2008, **100**, (7)
- [9] Garcia R. and Herruzo E. T.: 'The emergence of multifrequency force microscopy', *Nat Nano*, 2012, **7**, (4), pp. 217–226
- [10] Dietz C., et al.: 'Nanomechanical coupling enables detection and imaging of 5 nm superparamagnetic particles in liquid', *Nanotechnology*, 2011, **22**, (12), 125708
- [11] Garcia R., Proksch R.: 'Nanomechanical mapping of soft matter by bimodal force microscopy', *European Polymer Journal*, 2013, **49**, (8), pp. 1897–1906
- [12] Sahin O., et al.: 'High-resolution imaging of elastic properties using harmonic cantilevers', *Sensors and Actuators A: Physical*, 2004, **114**, (23), 183190
- [13] Sadewasser S., Villanueva G., Plaza J. A.: 'Modified atomic force microscopy cantilever design to facilitate access of higher modes of oscillation', *Review of Scientific Instruments*, 2006, **77**, (7), 073703
- [14] Felts J. R., King W. P.: 'Mechanical design for tailoring the resonance harmonics of an atomic force microscope cantilever during tipsurface contact', *Journal of Micromechanics and Microengineering*, 2009, **19**, (11), 115008
- [15] Xia Q., et al.: 'Shape and topology optimization for tailoring the ratio between two flexural eigenfrequencies of atomic force microscopy cantilever probe', *Frontiers of Mechanical Engineering*, 2014, **9**, (1), pp. 50–57
- [16] Cai J., et al.: 'A variable-width harmonic probe for multifrequency atomic force microscopy', *Applied Physics Letters*, 2015, **106**, (7), 071901
- [17] Bharaj G., et al.: 'Computational Design of Metallophone Contact Sounds', *ACM Trans. Graph.*, 2015, **34**, (6), pp. 223:1–223:13
- [18] Quek S. S., Liu G. R.: 'Finite Element Method: A Practical Course.', 2003, Elsevier Science
- [19] Ruppert M. G., Moheimani S. O. R.: 'Multimode Q Control in Tapping-Mode AFM: Enabling Imaging on Higher Flexural Eigenmodes', *Control Systems Technology, IEEE Transactions on*, 2016, **24**, (4), pp. 1149–1159
- [20] Petyt M.: 'Introduction to Finite Element Vibration Analysis', 1998, Cambridge University Press
- [21] Wang S. Y., Tai K., Wang M. Y.: 'An enhanced genetic algorithm for structural topology optimization', *International Journal for Numerical Methods in Engineering*, 2006, **65**, (1), pp. 18–44
- [22] Jakiela M. J., et al.: 'Continuum structural topology design with genetic algorithms', *Computer Methods in Applied Mechanics and Engineering* **186**, (24), pp. 339–356
- [23] Kim I. Y., deWeck O. L.: 'Variable chromosome length genetic algorithm for progressive refinement in topology optimization', *Structural and Multidisciplinary Optimization*, 2005, **29**, (6), pp. 445–456
- [24] Madeira J. F. A., Pina H. L., Rodrigues H. C.: 'GA topology optimization using random keys for tree encoding of structures', *Structural and Multidisciplinary Optimization*, 2010, **40** (1-6), pp. 227–240
- [25] Garcia-Lopez N. P., et al.: 'An improved robust topology optimization approach using multiobjective evolutionary algorithms', *Computers & Structures*, 2013, **125**, pp. 1–10.
- [26] Cowen A., et al.: 'PiezoMUMPs Design Handbook', 2014, **1.3**, MEMSCAP Inc.
- [27] Fairbairn M. W., Moheimani S. O. R., Fleming A. J.: 'Q Control of an Atomic Force Microscope Microcantilever: A Sensorless Approach'. *Microelectromechanical Systems, Journal of*, 2011, **20**, (6), pp. 1372–1381.
- [28] Ruppert M. G., Moheimani, S. O. R.: 'A novel self-sensing technique for tapping-mode atomic force microscopy', *Review of Scientific Instruments*, 2013, **84**, (12), 125006